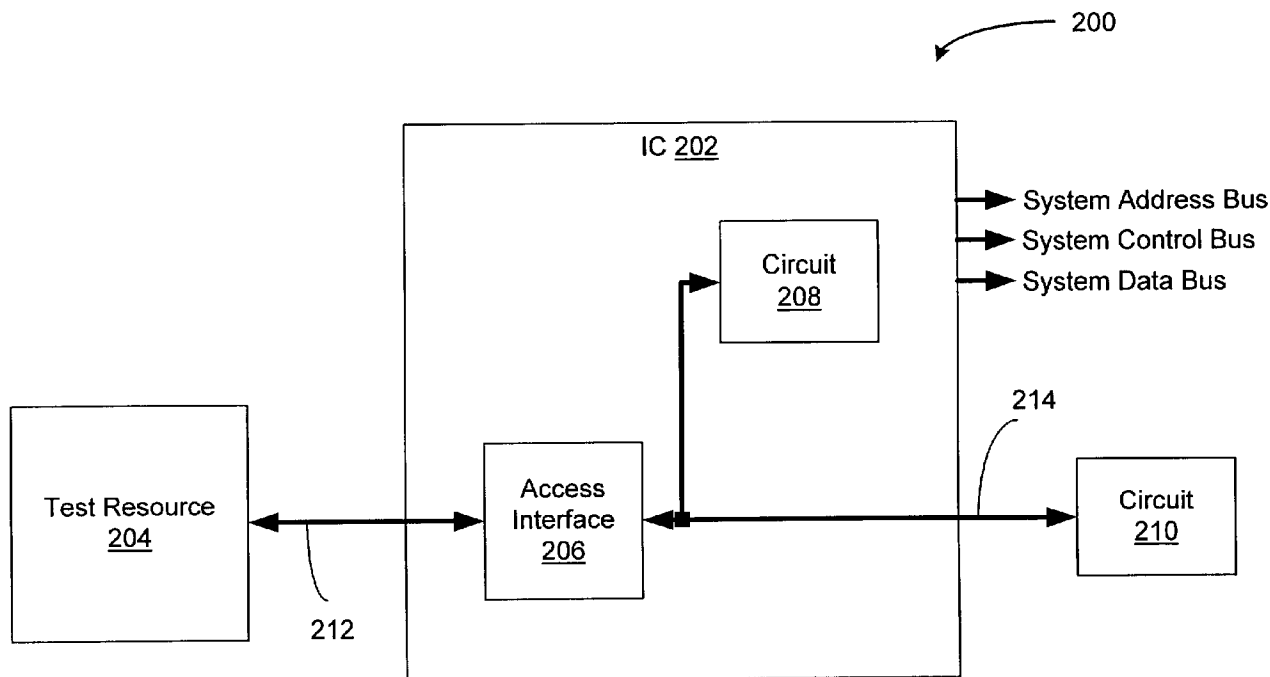




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(54) Titre : PROCÉDE ET APPAREIL PROCURANT UN ACCES OPTIMISE A DES CIRCUITS AUX FINS DE DEBOGAGE, PROGRAMMATION ET ESSAI  
 (54) Title: METHOD AND APPARATUS FOR PROVIDING OPTIMIZED ACCESS TO CIRCUITS FOR DEBUG, PROGRAMMING, AND TEST



(57) **Abrégé/Abstract:**

An access interface (206) for accessing electrical nodes of an electronic circuit (208) for programming, testing, and debugging the electronic circuit (208). The access interface (206) includes a protocol generator and a data generator that may be programmed to apply control and/or data sequences directly to the electronic circuit. The access interface (206) performs operational commands based upon a plurality of states included in a programmable state machine. By suitably programming the protocol generator, the data generator, and the state machine, electrical nodes of the electronic circuit can be accessed in reduced time using a reduced number of operations. The access interface (206) is controlled by a test resource apparatus (204), which communicates with the electronic circuit (208) connected to the access interface (206).